

Notice of References Cited

Application/Control No.

10/590,196

Applicant(s)/Patent Under
Reexamination
YANO ET AL.

Examiner

KEVIN SPINELLA

Art Unit

2885

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0015297	02-2002	Hayashi et al.	362/27
*	B	US-5,144,539	09-1992	Katoh et al.	362/256
*	C	US-4,992,916	02-1991	Henkes, John L.	362/255
*	D	US-2005/0179352	08-2005	Hayashi et al.	313/044
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1245898 A1	10-2002	European Patent	OKI et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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